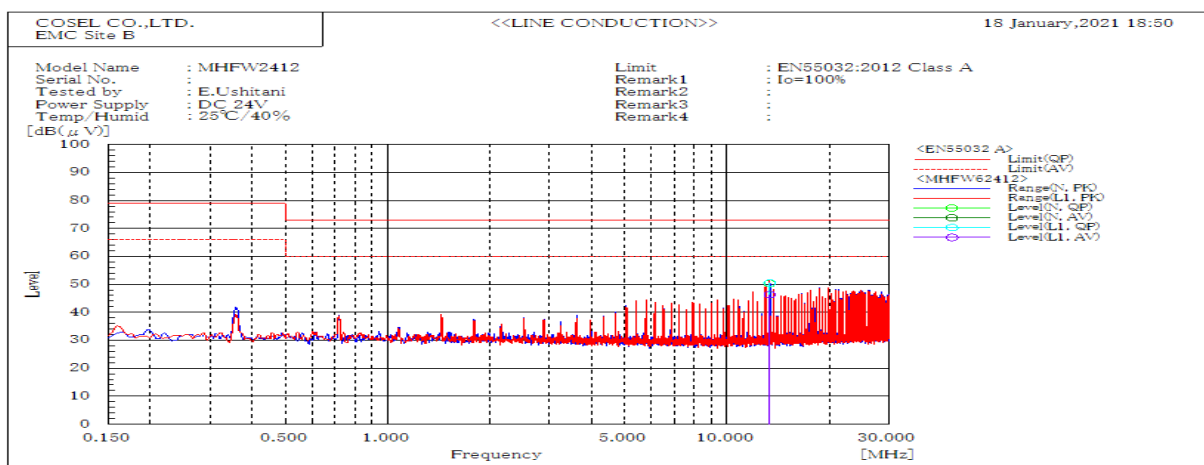
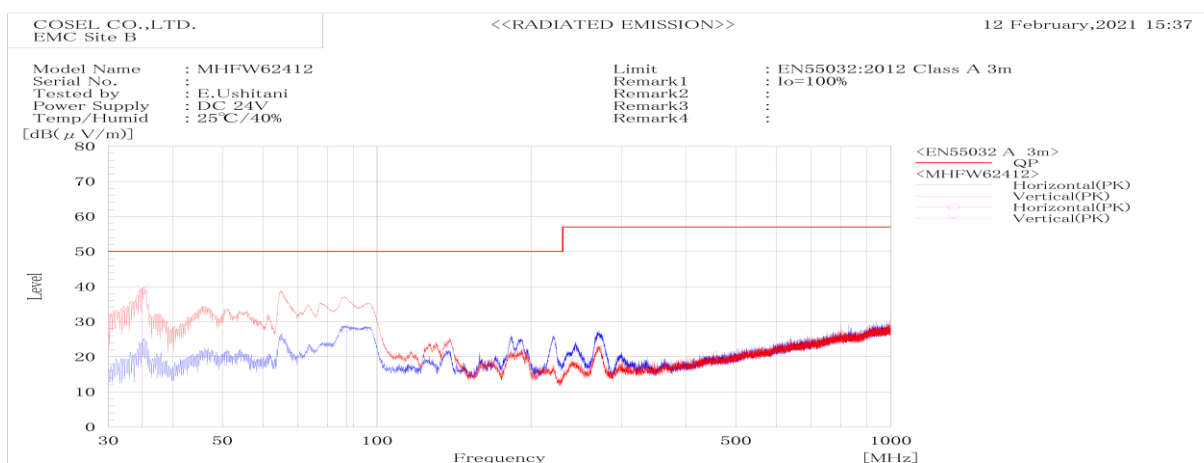


DATA SHEET

Model	MHFW62412	Date	05-Nov-21
Test	EMI	Temp.	25 degreeC
	Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



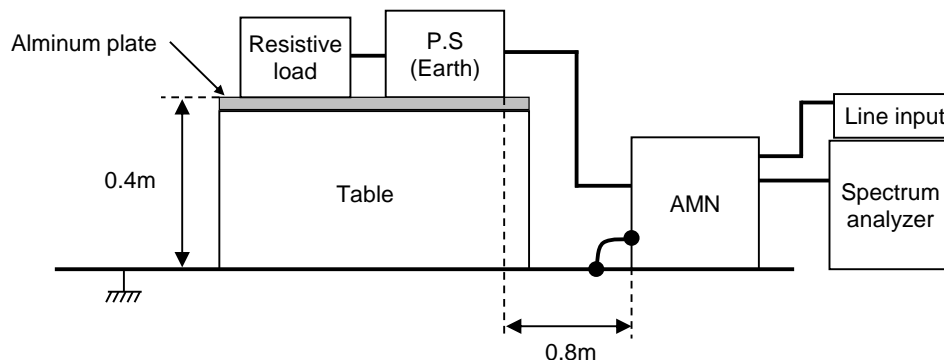
Frequency	Line	Level	Limit	Margin	Pass/Fail	Remark
MHz		dB(μV)	dB(μV)	dB		
		QP	AV	QP	AV	
13.351	L1	50.5	46.3	73	60	22.5
13.352	N	50.4	46.3	73	60	22.6



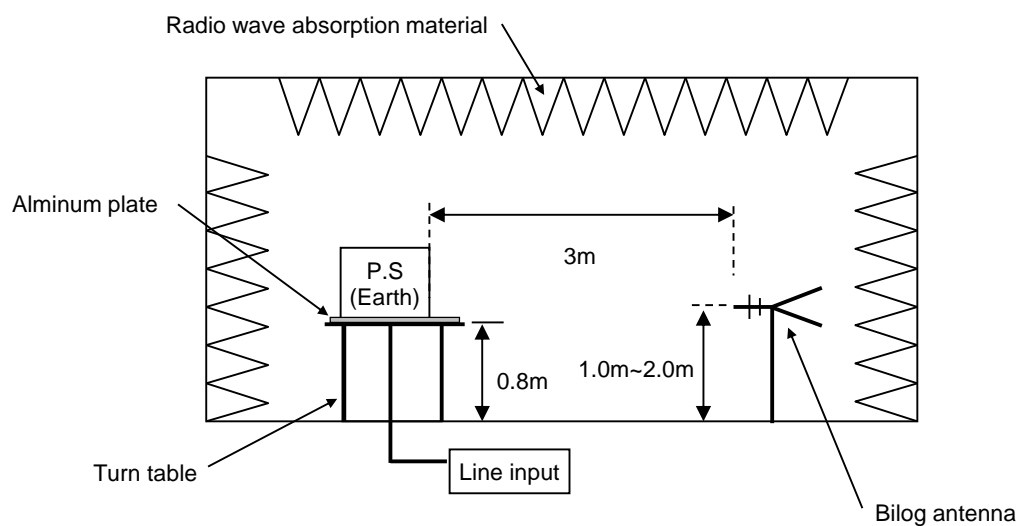
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB		cm	deg	
			QP	QP	QP				
87.462	H	Stable	28.1	50	21.9	Pass	198.4	67.1	
34.919	V	Stable	39.3	50	10.7	Pass	100	16.2	

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission



Conditions

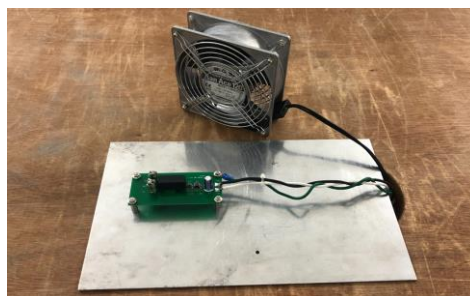
Test : EMI
Model Name: MHFW6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

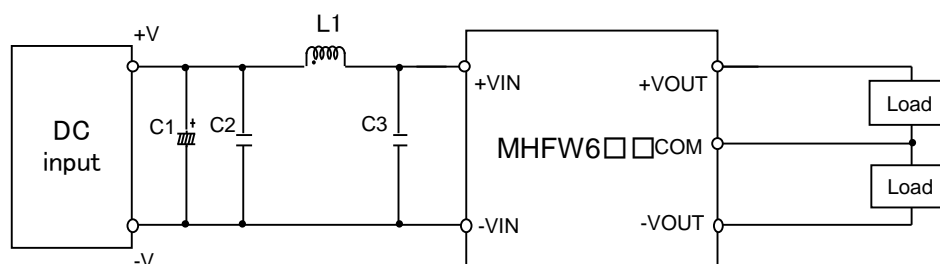


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	—
	MHFS648□□	—
C2 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 μ H Inductor (LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 μ H Inductor (LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 μ H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING)